

Notice of References Cited	Application/Control No. 10/714,182		Applicant(s)/Patent Under Reexamination CHRISTIAN, JOHN P.	
	Examiner BRIAN P. YENKE		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0156227	08-2003	Kondo, Tetsujiro	348/714
*	B	US-6,161,156	12-2000	Suzuki et al.	710/300
*	C	US-2002/0008779	01-2002	Ju et al.	348/552
*	D	US-6,359,636	03-2002	Schindler et al.	715/846
*	E	US-2005/0183119	08-2005	Hofrichter et al.	725/046
*	F	US-2003/0076346	04-2003	Yun, Choi-Young	345/718
*	G	US-2002/0100045	07-2002	Rafey et al.	725/46
*	H	US-6,788,882	09-2004	Geer et al.	386/116
*	I	US-6,662,365	12-2003	Sullivan et al.	725/25
*	J	US-6,134,376	10-2000	Lee et al.	386/46
*	K	US-2002/0180890	12-2002	Milne et al.	348/572
*	L	US-2003/0137602	07-2003	Chang et al.	348/552
*	M	US-2004/0031060	02-2004	Kondo, Tetsujiro	725/131

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-6-169440	06-1994	JAPAN	TAJIMA et al	H04N 5/64
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.